

**Field-induced charged-device model
test method for electrostatic
discharge withstand thresholds
of microelectronic components**

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IEC/PAS 62162:2000

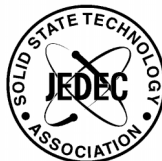
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PUBLICLY AVAILABLE SPECIFICATION



INTERNATIONAL
ELECTROTECHNICAL
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Reference number
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JEDEC STANDARD

Test Method C101

Field-Induced Charged-Device Model Test Method for Electrostatic Discharge Withstand Thresholds of Microelectronic Components

JESD22-C101

MAY 1995

ELECTRONIC INDUSTRIES ASSOCIATION
ENGINEERING DEPARTMENT



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INTERNATIONAL ELECTROTECHNICAL COMMISSION

FIELD-INDUCED CHARGED-DEVICE MODEL TEST METHOD FOR ELECTROSTATIC DISCHARGE WITHSTAND THRESHOLDS OF MICROELECTRONIC COMPONENTS

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IEC-PAS 62162 was submitted by JEDEC and has been processed by IEC technical committee 47: Semiconductor devices.

The text of this PAS is based on the following document:

This PAS was approved for publication by the P-members of the committee concerned as indicated in the following document:

Draft PAS	Report on voting
47/1462/PAS	47/1495/RVD

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